

## DATA SHEET

Model MGFS804805

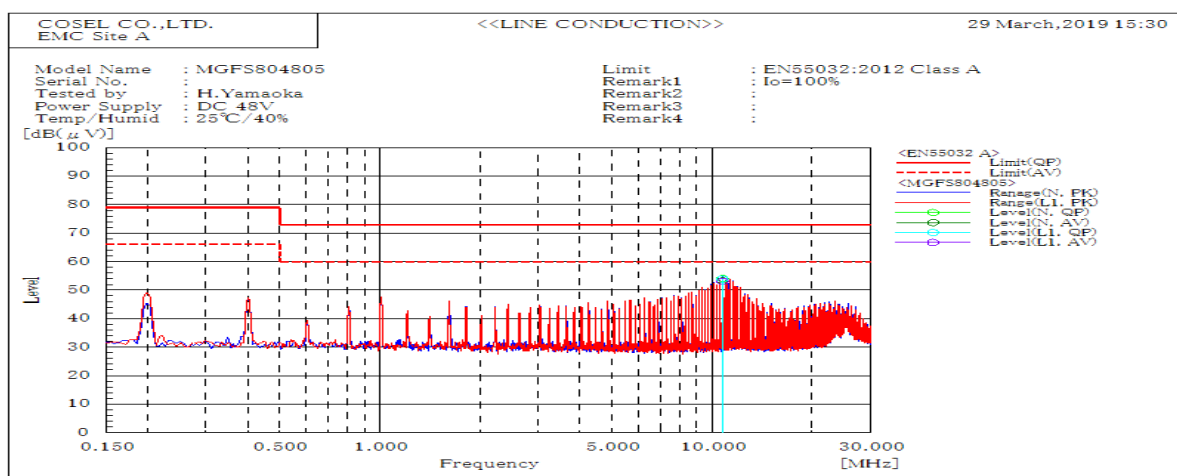
Date 23-Apr-19

Test EMI  
Line conduction & Radiated emission

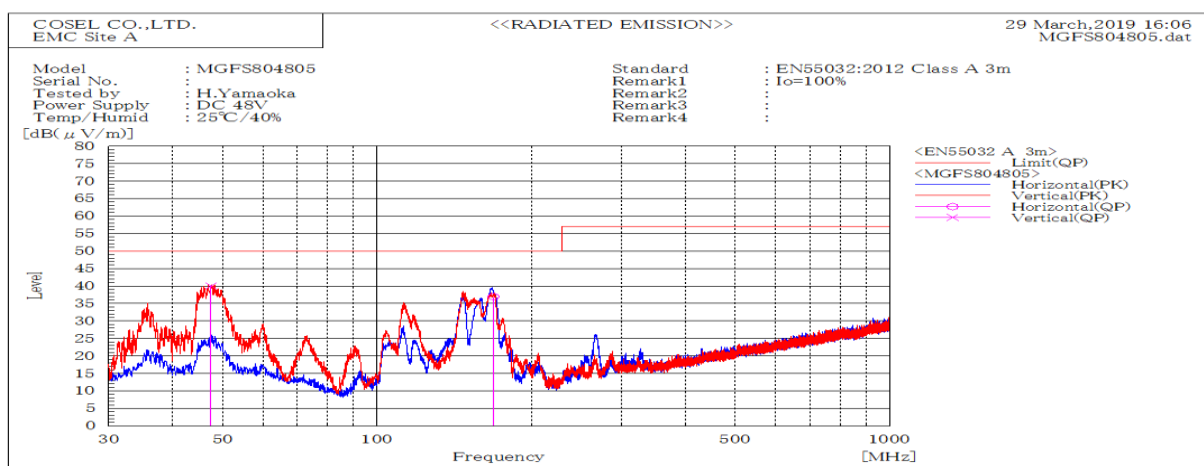
Temp. 25 degreeC

Humid. 40 %RH

Tested by H.Yamaoka



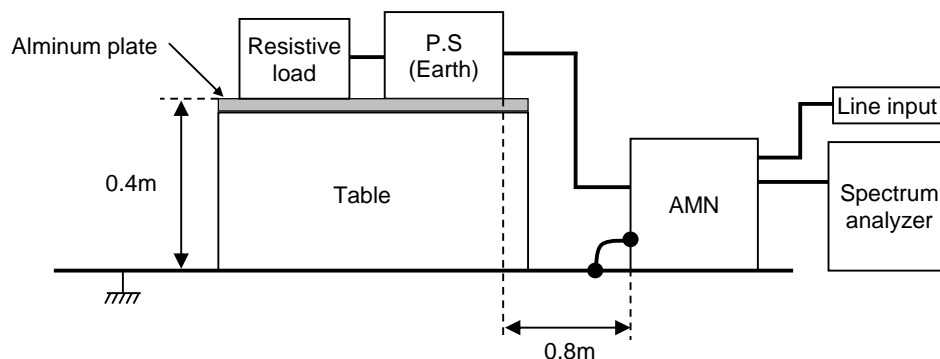
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
10.729	L1	53.9	53.2	73	60	19.1	6.8	Pass	
10.725	N	54.1	53.3	73	60	18.9	6.7	Pass	



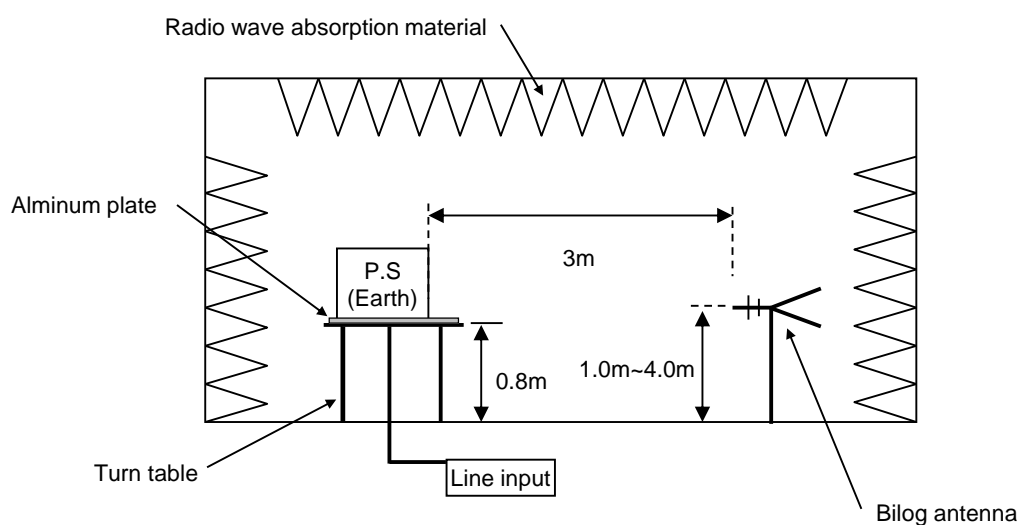
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB		cm	deg	
			QP	QP	QP				
168.807	H	Stable	36.9	50	13.1	Pass	182.1	351.3	
47.504	V	Stable	40	50	10	Pass	100.2	34.6	

DATA SHEET		Date	23-Apr-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka

## 1. Line conduction



## 2. Radiated emission



# Conditions

Test : EMI

Model Name : MGFS80□□

## ○Photographs of Test Set-Up LINE CONDUCTION



## ○Testing circuitry

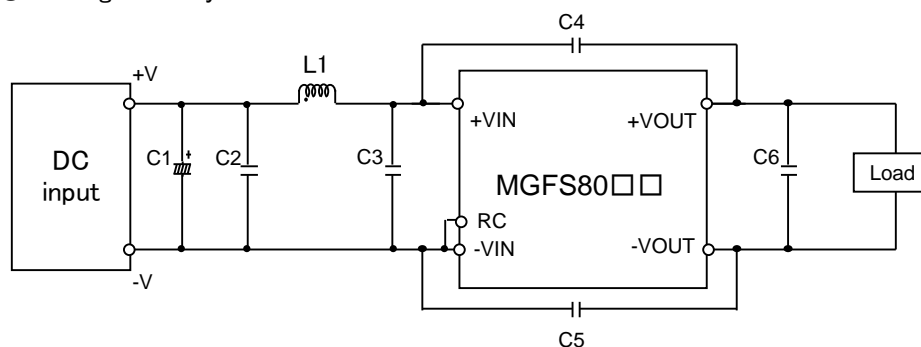


Fig.1 Testing circuitry

- C1 : MGFS8024□□ 63V 470  $\mu$ F Electrolytic capacitor (ELXZseries NIPPON CHEMI-CON)  
MGFS8048□□ 100V 220  $\mu$ F Electrolytic capacitor (KYseries NIPPON CHEMI-CON)
- C2 : MGFS8024□□ 50V 10  $\mu$ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)  
MGFS8048□□ 100V 4.7  $\mu$ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C3 : MGFS8024□□ 50V 10  $\mu$ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)  
MGFS8048□□ 100V 4.7  $\mu$ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C4,C5 : MGFS8024□□ 2kV 2200pF Ceramic capacitor  
(GR443QR73D222KW01 MURATA MANUFACTURING)  
MGFS8048□□ 2kV 3300pF Ceramic capacitor  
(GR443QR73D332KW01 MURATA MANUFACTURING)
- C6 : MGFS8024□□ 25V 22  $\mu$ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)  
MGFS8048□□ 25V 22  $\mu$ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
- L1 : MGFS8024□□ 12.0A 1.8  $\mu$ H Inductor (SRP7050TA-1R8M BOURNS)  
MGFS8048□□ 8.0A 3.3  $\mu$ H Inductor (SRP7050TA-3R3M BOURNS)

## RADIATED EMISSION

